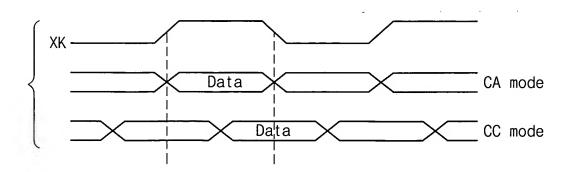
Fig. 1

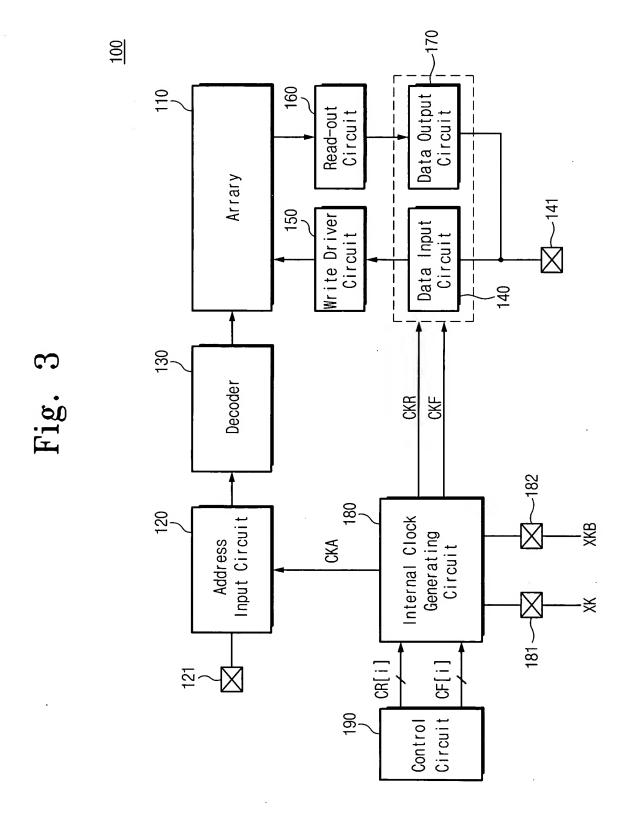
Operating Frequency Range
of Memory Device

Operating Frequency Range
of Test Equipment

Synchronization Range

Fig. 2





180 SMDR • • • E <u>a</u> 8 -1221T-(td1+td2+td3+td4) 1+T/8 td2 CLK_0T CLK_45T REGEN 1190 CR[i] td4 1150 MÜX 0UT1 0UT2 **0UT3** 1140 絽 td3 1200 DRV 1130 M CLKref1 E TE 1120 OUT1R + OUT2R + OUT3R + OUTIR OUTZF td4 REGEN 1110

Fig. 4A

 ~ 1370 ~1380 ~1420 180 SMPF £ <u>B</u> ഒ -1421T-(td1+td2+td3+td4) 1+1/8 H td2 CLK_901 Fig. 4B CLK_135T td4 REGEN 1390 CF[i] 1350 ¥ M 0UT1 **0UT2** tg3 1340 DRV 1330 CLKref2 EE T 1400 td2 DRV M -0UT3R -0UT3F E] 1320 0UT1F ▲ 0UT2F ▲ 0UT3F -OUT2R OUT1F 1500 to4 REGEN REGEN 宣 tot 1310 1410-

Fig. 5

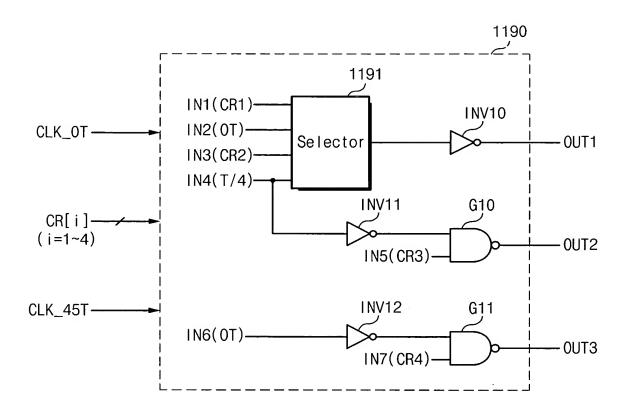


Fig. 6

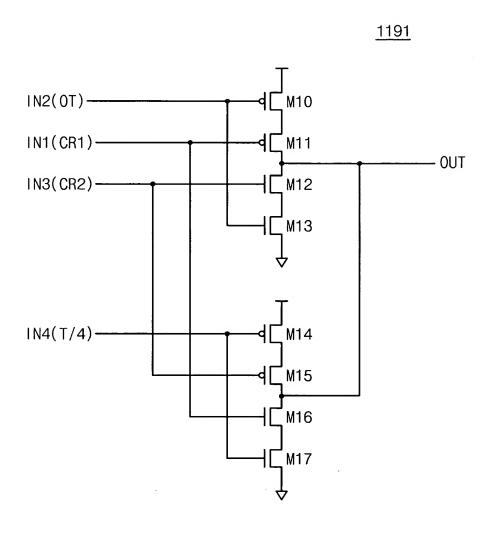


Fig. 7A

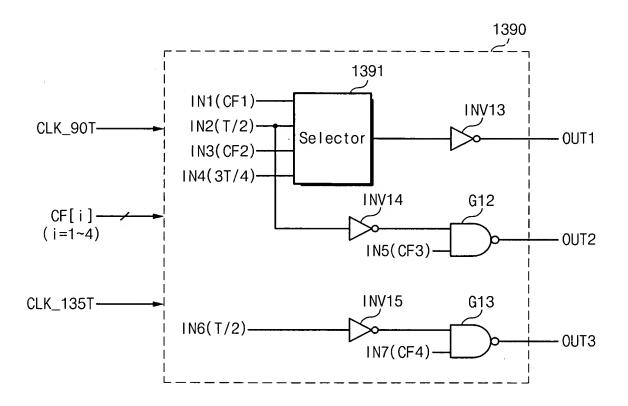


Fig. 7B

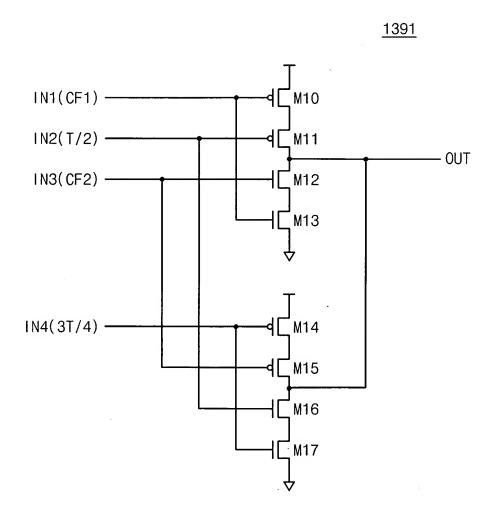
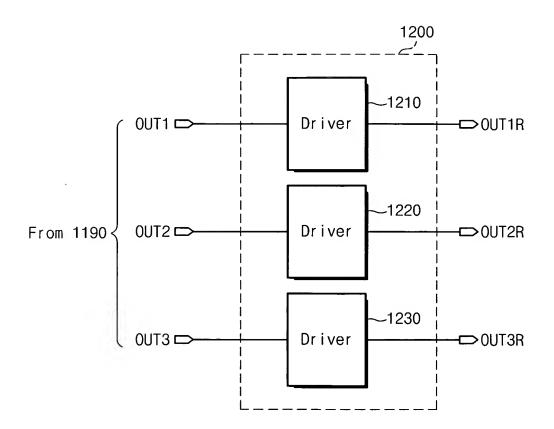
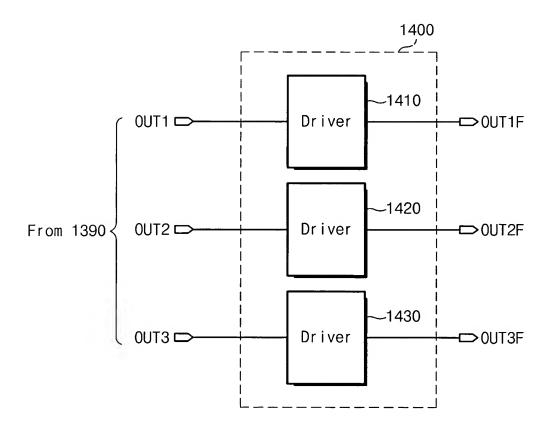


Fig. 8



1210,1220,1230 _M28 ω. INV24 IN/23 Fig. 9 M25 M19 A INV21 INÝ16

Fig. 10



1250 --4 L M40 ~INV26 ~INV28 INV32 Fig. 11 IN/31 IN/30 I NV29 M30] ► M36_] **G**14 OUT1R DOUT2F DO

Fig. 12

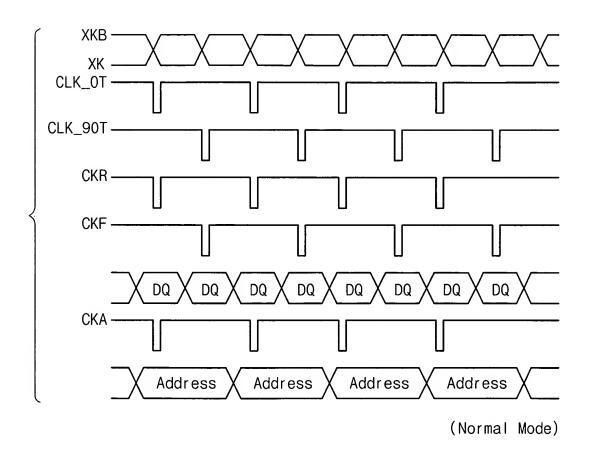
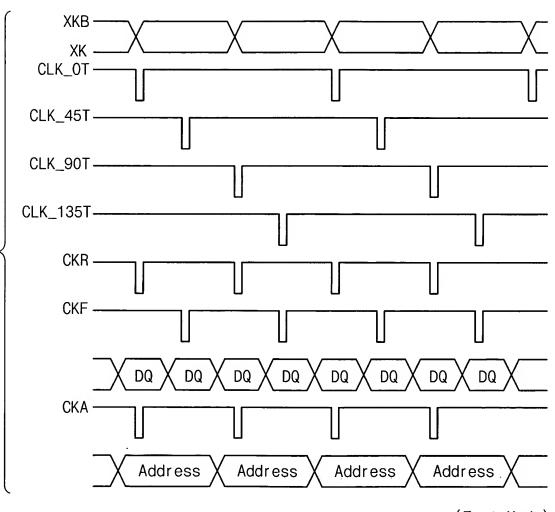


Fig. 13



(Test Mode)